In-Vehicle Networking/Autonomous Vehicle Security for Internet of Things/Vehicles

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Message from the Guest Editors

Dear Colleagues,

In recent years, vehicles have become one of the most common examples in the area of ICT convergence applications and services. At the same time, potential cybersecurity threats on vehicle systems and networks are rapidly growing. In order to provide more secure and reliable services for vehicles, both security and safety should be carefully considered.

The topics of interest include but are not limited to:

- Automotive networking;
- In-vehicle network security;
- Autonomous vehicle security;
- V2X applications and services for security;
- Internet of Things/Vehicles;
- Industrial Internet of Things for vehicle security;
- Safety detection and fault management;
- Security and safety on an automotive virtualized platform;
- Performance and fault simulation;
- Platform virtualization.

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Guest Editors

SpecialIssue

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Message from the Editor-in-Chief

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